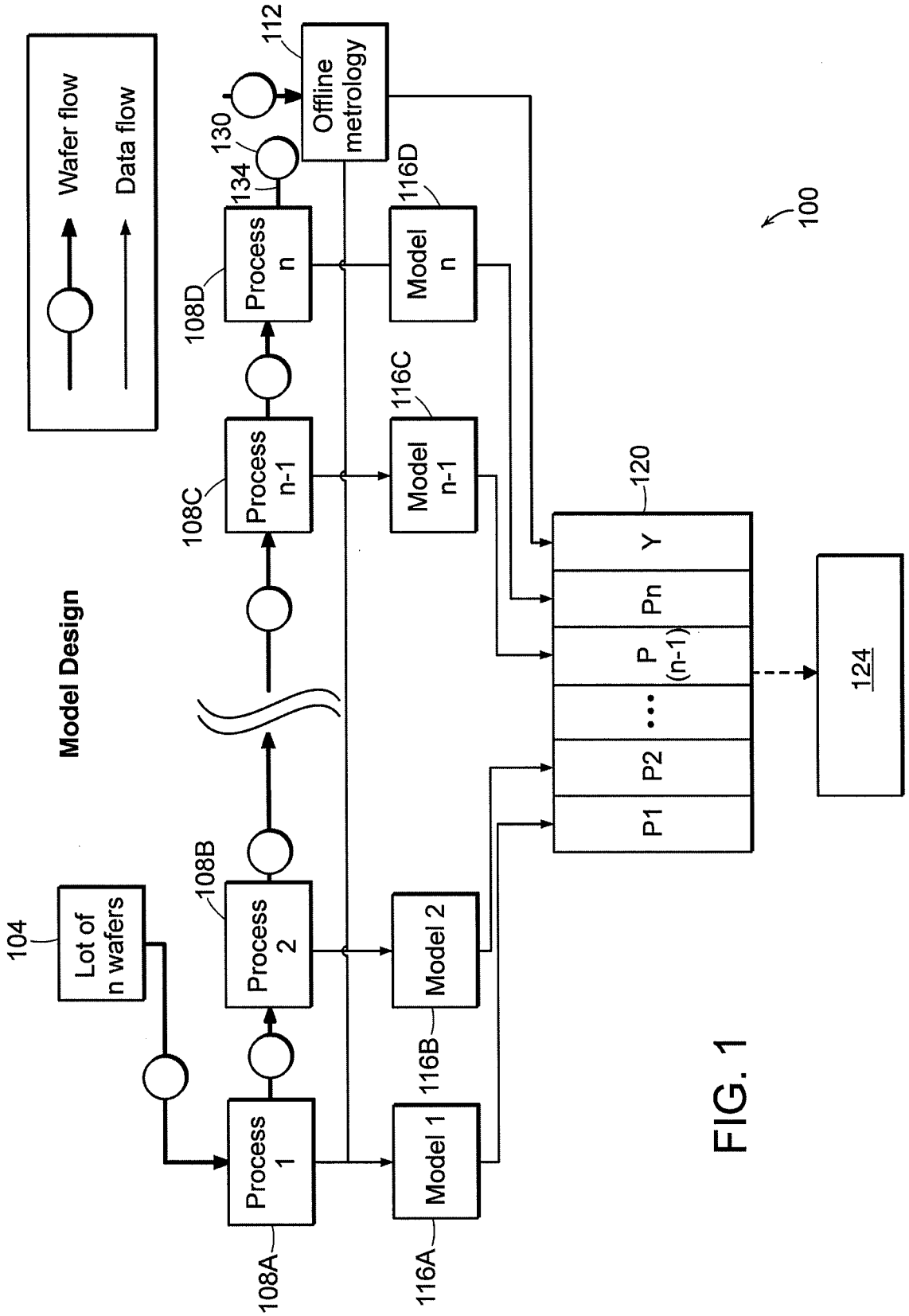

Wafer flow
Data flow
Model Design
104
Lot of n wafers
108A
Process 1
108B
Process 2
108C
Process n-1
108D
Process n
112
Offline metrology
130
134
116A
Model 1
116B
Model 2
116C
Model n-1
116D
Model n
120
P1
P2
P (n-1)
Pn
Y
124
100

FIG. 1

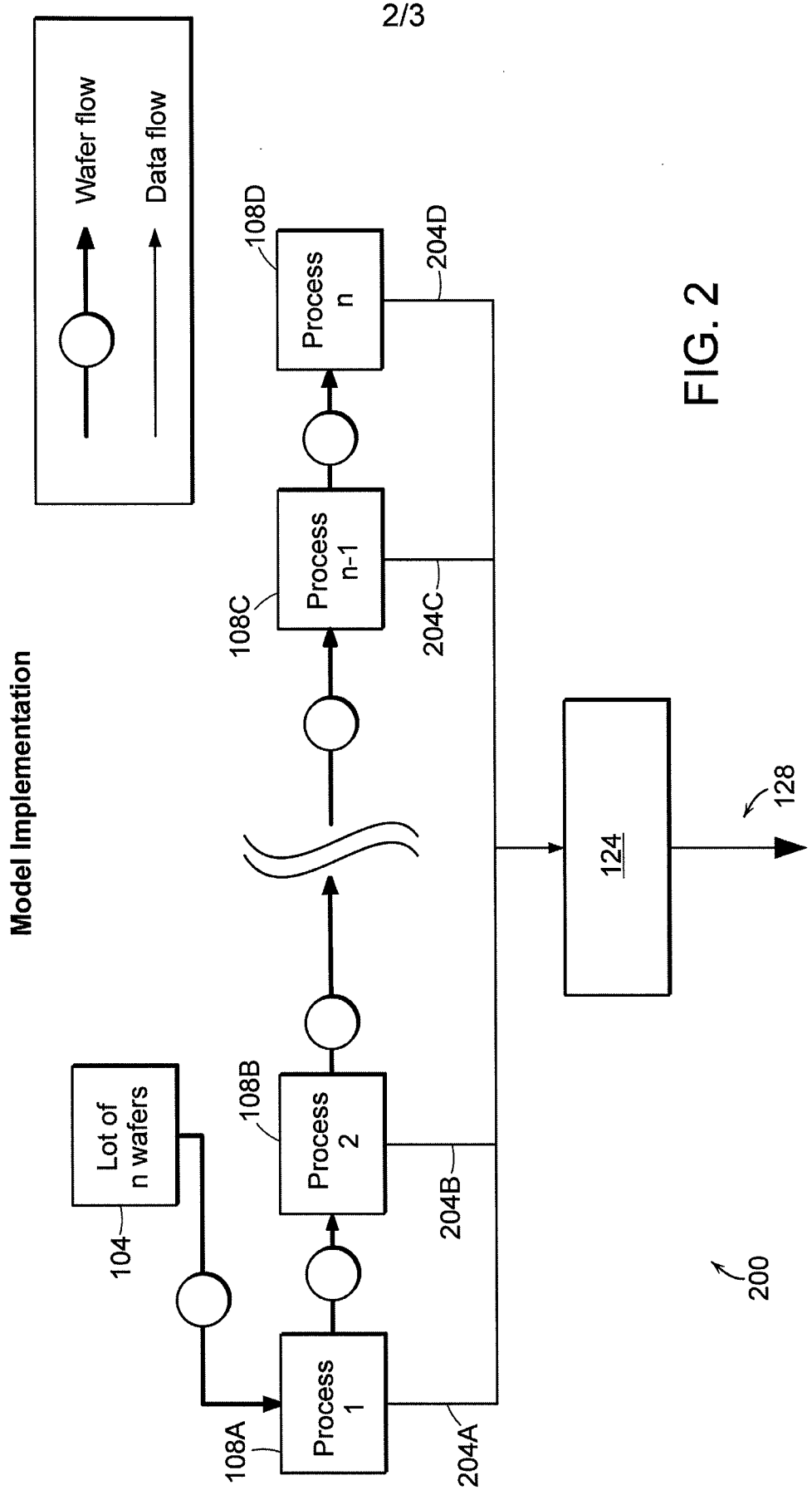

Wafer flow
Data flow
Model Implementation
Lot of n wafers
104
Process 1
108A
Process 2
108B
Process n-1
108C
Process n
108D
204A
204B
204C
204D
124
128
200

FIG. 2

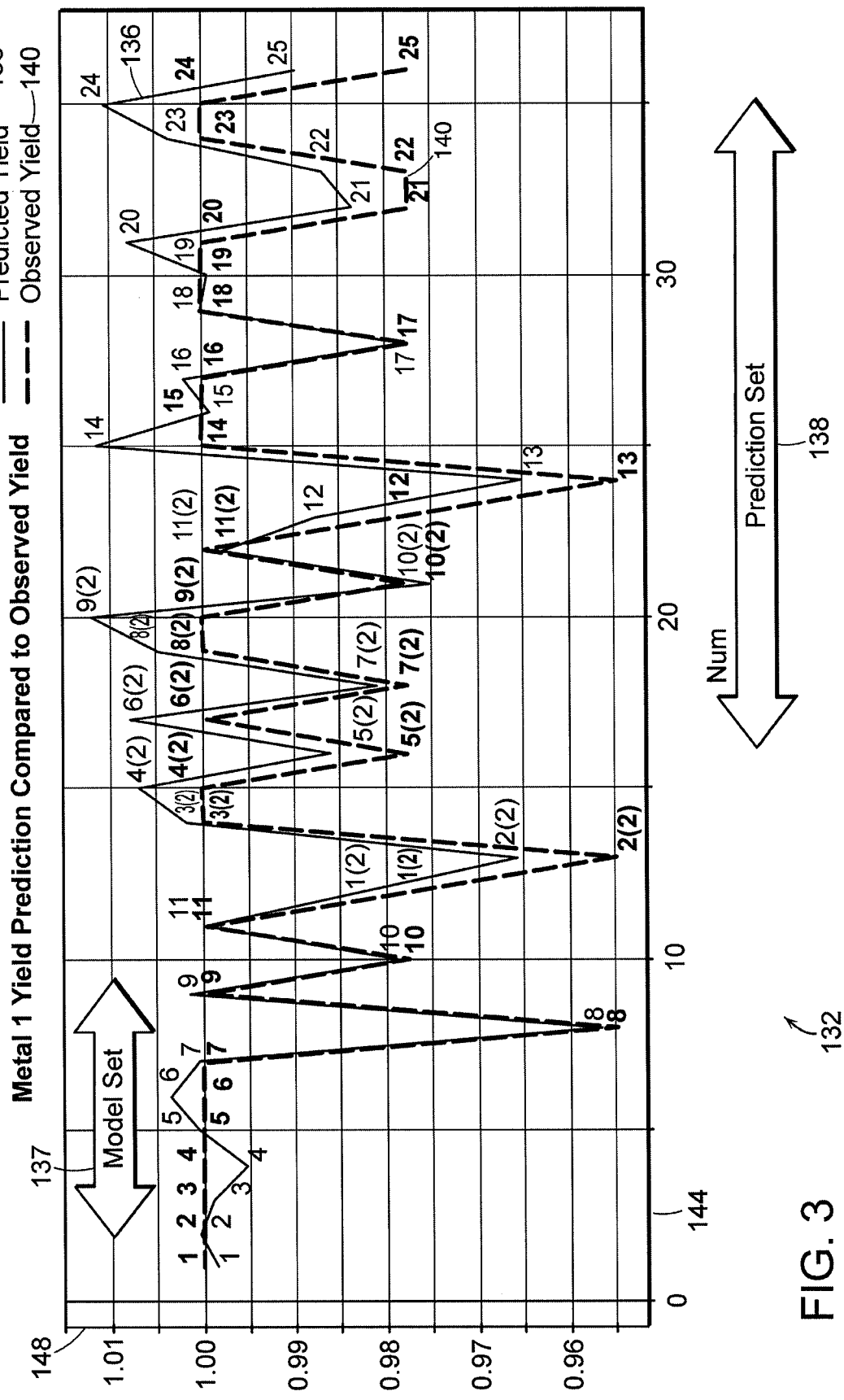

Metal 1 Yield Prediction Compared to Observed Yield
Predicted Yield 136
Observed Yield 140
Model Set
Prediction Set
Num
137
138
144
148
132
1.01
1.00
0.99
0.98
0.97
0.96
0
10
20
30

FIG. 3